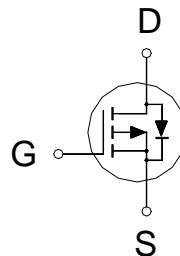


P-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	-20V
R _{DSON} (MAX.)	9.5mΩ
I _D	-20A



Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±8	V
Continuous Drain Current	T _A = 25 °C	I _D	-20	A
	T _A = 70 °C		-15	
Pulsed Drain Current ¹		I _{DM}	-80	
Avalanche Current		I _{AS}	-15	
Avalanche Energy	L = 0.1mH, I _D =-15A, R _G =25 Ω	E _{AS}	11.25	mJ
Repetitive Avalanche Energy ²	L = 0.05mH	E _{AR}	5.6	
Power Dissipation	T _A = 25 °C	P _D	2.5	W
	T _A = 70 °C		1.25	
Operating Junction & Storage Temperature Range		T _J , T _{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	6	50	°C / W
Junction-to-Ambient ³	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

³50°C / W when mounted on a 1 in² pad of 2 oz copper.

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.4	-0.75	-1.2	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 8\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -16\text{V}, V_{GS} = 0\text{V}$			-1	μA
		$V_{DS} = -12\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			-10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = -5\text{V}, V_{GS} = -4.5\text{V}$	-20			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = -4.5\text{V}, I_D = -15\text{A}$		7.8	9.5	$\text{m}\Omega$
		$V_{GS} = -2.5\text{V}, I_D = -8\text{A}$		10.3	12.5	
		$V_{GS} = -1.8\text{V}, I_D = -5\text{A}$		14.5	18	
Forward Transconductance ¹	g_{fs}	$V_{DS} = -5\text{V}, I_D = -15\text{A}$		32		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0\text{V}, V_{DS} = -10\text{V}, f = 1\text{MHz}$		7660		pF
Output Capacitance	C_{oss}			596		
Reverse Transfer Capacitance	C_{rss}			510		
Gate Resistance	R_g	$V_{GS} = 15\text{mV}, V_{DS} = 0\text{V}, f = 1\text{MHz}$		3.0		Ω
Total Gate Charge ^{1,2}	$Q_g(V_{GS}=-4.5\text{V})$	$V_{DS} = -10\text{V}, V_{GS} = -4.5\text{V}, I_D = -15\text{A}$		51		nC
	$Q_g(V_{GS}=-2.5\text{V})$			32		
Gate-Source Charge ^{1,2}	Q_{gs}			4.9		
Gate-Drain Charge ^{1,2}	Q_{gd}			13		
Turn-On Delay Time ^{1,2}	$t_{d(on)}$	$V_{DS} = -10\text{V}, I_D = -1\text{A}, V_{GS} = -4.5\text{V}, R_{GS} = 6\Omega$		25		ns
Rise Time ^{1,2}	t_r			55		
Turn-Off Delay Time ^{1,2}	$t_{d(off)}$			150		
Fall Time ^{1,2}	t_f			65		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^\circ\text{C}$)						
Continuous Current	I_S				-3.5	A
Pulsed Current ³	I_{SM}				-14	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{GS} = 0\text{V}$			-1.2	V

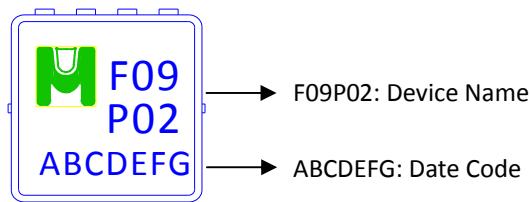
¹Pulse test : Pulse Width $\leq 300\text{ }\mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

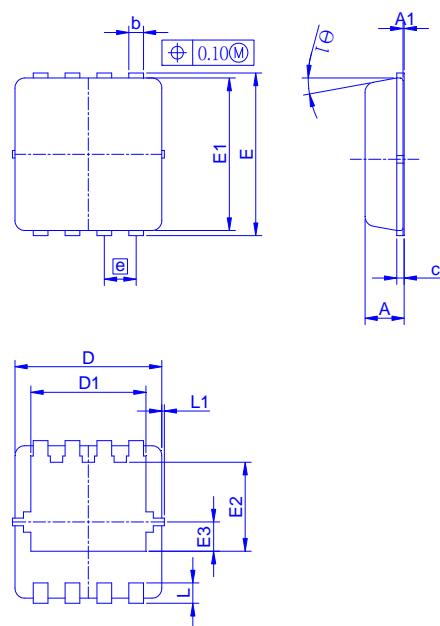
³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: EMF09P02V for EDFN 3 x 3



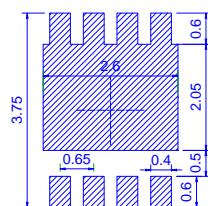
Outline Drawing



Dimension in mm

Dimension	A	A1	b	c	D	D1	E	E1	E2	E3	e	L	L1	Θ1
Min.	0.70	0	0.24	0.10	2.95	2.25	3.15	2.95	1.65			0.30		0°
Typ.	0.80		0.30	0.152	3.00	2.35	3.20	3.00	1.75	0.575	0.65	0.40	0.13	10°
Max.	0.90	0.05	0.37	0.25	3.15	2.45	3.40	3.15	1.96			0.50		12°

Recommended minimum pads



TYPICAL CHARACTERISTICS

